

Fig. 1 is a perspective view of a semiconductor device 1. The device includes a substrate 11 with a top layer 12. A central region 3 contains a stack of layers 38 and 39, with a central block 31. A probe 75 is positioned above the central region. A complex assembly 5 is mounted on the right side of the substrate, including a base 52, a vertical support 53, and a probe 71. A coordinate system with X, Y, and Z axes is shown at the bottom.

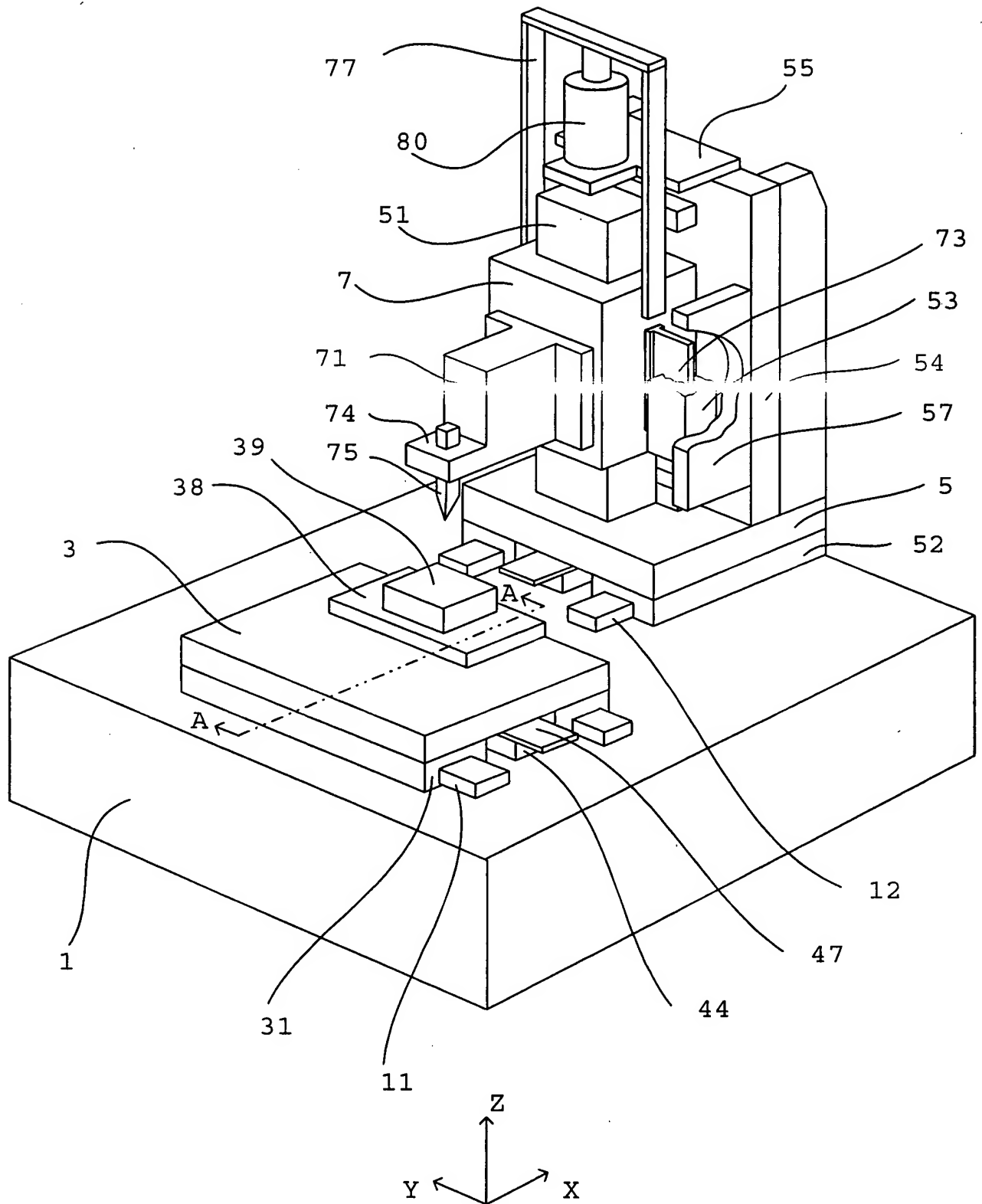


FIG. 2

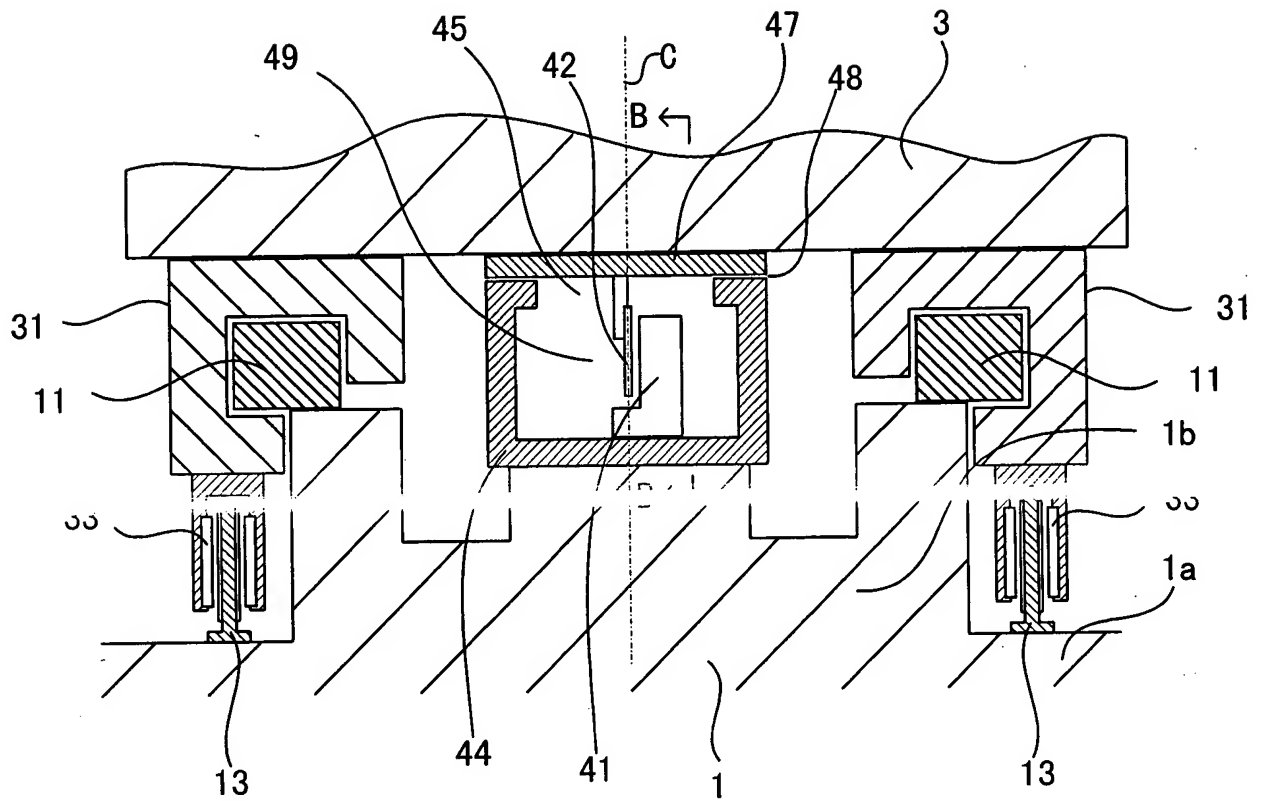


FIG. 3

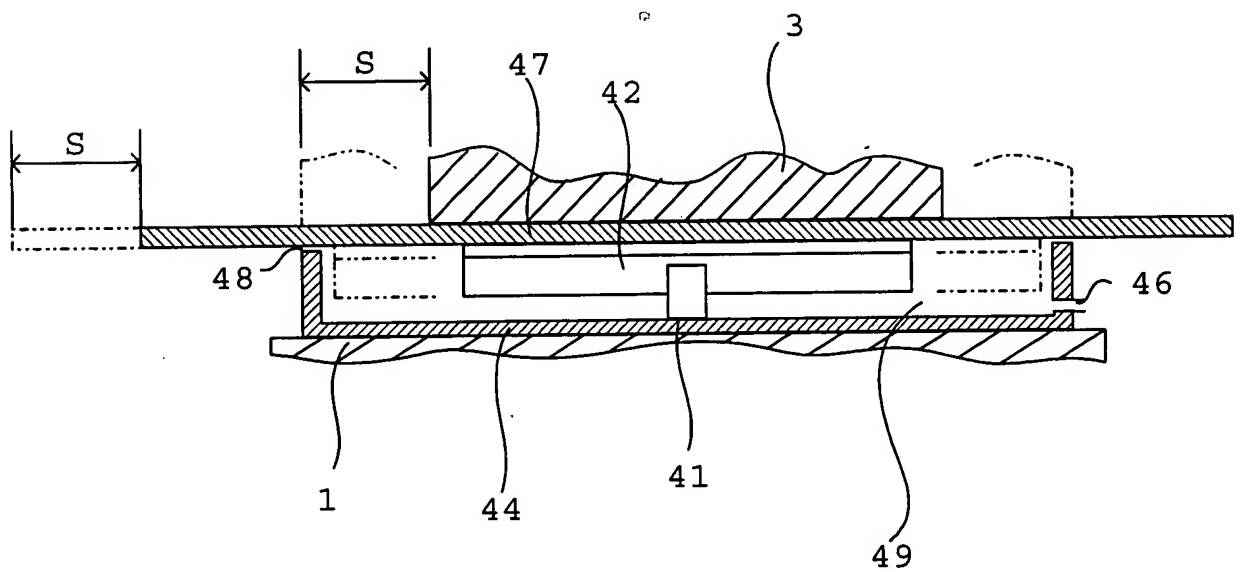


FIG. 4

